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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Tang et al.

Serial No. 09/715,815 ✓

Filing Date: November 16, 2000 ✓

For: *Mass Spectrometer System Including  
a Double Ion Guide Interface and  
Method of Operation*

Examiner: John R. Lee

Art Unit: 2881

AMENDMENT/RESPONSE

Date: June 11, 2002

CERTIFICATE OF MAILING

I hereby certify that this document or fee is being deposited with the United States Postal Service as First Class Mail address to Box Non-Fee Amendment, Assistant Commissioner for Patents, Washington, D.C. 20231 on June 11, 2002.

SIGNED

*Kathryn Marley*  
Kathryn Marley

**BOX NON-FEE AMENDMENT**

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

This is in response to the Office Action mailed March 14, 2002. ✓

In the Claims: ✓

Please amend the following claims to read as follows:

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1. A mass spectrometer system including a mass analyzer disposed in a high vacuum chamber for analyzing sample ions formed at atmospheric pressure and directed to the analyzer through intermediate vacuum chambers in which sample ions and solvent molecules form adduct ions with a reduction of sample ion current including:

first and second evacuated chambers directly preceding the mass analyzer chamber with the first chamber being at a higher pressure than the second chamber,

a first multipole ion guide in the first chamber for guiding ions into said second chamber, a second multipole ion guide in the second chamber for guiding ions from the first chamber into the high vacuum chamber for mass analysis, and

means associated with one or both of said first and second multipole ion guides for increasing the translational kinetic energy of the adduct ions so that at the vacuum pressure of the